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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

10/18

APPL NUM 10017262	FILING DATE 12/14/2001	CLASS 250	SUBCLASS	GAU 2878	EXAMINER <i>J. M. S.</i>
**APPLICANTS: Adler David; Marcus Matthew;					
**CONTINUING DATA VERIFIED:					
** FOREIGN APPLICATIONS VERIFIED:					
PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>			
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiner's initials			<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO P960	
TITLE : Photoelectron emmission microscope for wafer and reticle inspection					
<small>U.S. DEPT. OF COMM /PAT & TM-PTO-426L (Rev. 12-94)</small>					

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.	Print Fig.
TERMINAL		Primary Examiner		
DISCLAIMER		PREPARED FOR ISSUE Application Examiner		
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